IN THE CLAIMS

This listing of claims replaces all prior versions and listings of the claims in the abovereferenced application.

(Original) A III-nitride light emitting device comprising:

a first layer of first conductivity type;

- a first layer of second conductivity type; an active region;
- a tunnel junction, the tunnel junction comprising:

a second layer of first conductivity type having a dopant concentration greater than the first layer of first conductivity type; and

a second layer of second conductivity type having a dopant concentration greater than the first layer of second conductivity type;

- a third layer of first conductivity type;
- a first contact electrically connected to the first layer of first conductivity type; and a second contact electrically connected to the third layer of first conductivity type; wherein:

the first and second contacts comprise the same material;

the first and second contact material has a reflectivity to light emitted by the active region greater than 75%;

the active region is disposed between a layer of first conductivity type and a layer of second conductivity type; and

the tunnel junction is disposed between the first layer of first conductivity type and the third layer of first conductivity type.

2. (Original) The device of claim 1 wherein:

the second layer of first conductivity type has a dopant concentration ranging from about 10¹⁸cm⁻³ to about 5×10²⁰cm⁻³; and

the second layer of second conductivity type has a dopant concentration ranging from about 10¹⁸cm⁻³ to about 5x10²⁰cm⁻³.

3. (Original) The device of claim 1 wherein the second layer of first conductivity type has a dopant concentration ranging from about $2x10^{20}$ cm⁻³ to about $4x10^{20}$ cm⁻³.

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- 4. (Original) The device of claim 1 wherein the second layer of second conductivity type has a dopant concentration ranging from about 7×10^{19} cm⁻³ to about 9×10^{19} cm⁻³.
- (Original) The device of claim 1 wherein the tunnel junction has a voltage drop ranging from between about 0V to about 1V when operated in reverse-biased mode.
- 6. (Original) The device of claim 1 wherein the tunnel junction has a voltage drop ranging from between about 0.1V to about 1V when operated in reverse-biased mode.
 - 7. (Original) The device of claim 1 wherein:

the second layer of first conductivity type has a thickness ranging from about 1 nm to about 50 nm; and

the second layer of second conductivity type has a thickness ranging from about 1 nm to about 50 nm.

- 8. (Original) The device of claim 1 wherein the tunnel junction has a thickness ranging from about 2 nm to about 100 nm.
- 9. (Original) The device of claim 1 further comprising a textured layer disposed between the third layer of first conductivity type and the second contact.
- 10. (Original) The device of claim 9 wherein the textured layer comprises islands of semiconductor material and pockets between the islands.
- 11. (Original) The device of claim 10 wherein the islands of semiconductor material comprise about 10% to about 90% of a volume of the textured layer.
- 12. (Original) The device of claim 10 wherein the islands of semiconductor material comprise about 10% to about 50% of a volume of the textured layer.
 - 13. (Original) The device of claim 10 wherein the pockets are filled with air.
- 14. (Original) The device of claim 10 wherein the pockets are at least partially filled with a material having an index of refraction less than about 2.
- 15. (Original) The device of claim 10 wherein the second contact is formed over the textured layer and fills the pockets.
- 16. (Original) The device of claim 9 wherein the textured layer has a thickness between about 200 Å and about 10,000 Å.
- 17. (Original) The device of claim 9 wherein the textured layer has a thickness between about 500 Å and about 4000Å.
- 18. (Original) The device of claim 9 wherein the second contact is bonded to the textured layer.

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- 19. (Original) The device of claim 18 further comprising at least one void disposed between the textured layer and the second contact.
 - 20. (Original) The device of claim 1 further comprising:
 - a submount;

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- a first interconnect connecting the first contact to the submount; and
- a second interconnect connecting the second contact to the submount.
- 21. (Original) The device of claim 20 further comprising:
- a plurality of leads connected to the submount; and
- a lens overlying the submount.
- (Original) The device of claim 21 further comprising: 22.
- a heat sink disposed between the leads and the submount.
- 23. (Original) The device of claim 1 wherein the first and second contacts comprise aluminum.
- (Original) The device of claim 1 wherein at least one of the first and second 24. contacts comprises a multilayer contact.
- 25. (Original) The device of claim 24 wherein the multilayer contact comprises a first layer of aluminum and a second layer overlying the first layer, the second layer comprising a material selected from a group consisting of Al-Si, Al-Si-Ti, Al-Cu, and Al-Cu-

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- (Original) A III-nitride light emitting device comprising:
- a first layer of first conductivity type;
- a first layer of second conductivity type;
- an active region;
- a tunnel junction, the tunnel junction comprising:
- a second layer of first conductivity type having a dopant concentration greater than the first layer of first conductivity type; and
- a second layer of second conductivity type having a dopant concentration greater than the first layer of second conductivity type; and
- a textured layer overlying the tunnel junction;
- whercin the active region is disposed between a layer of first conductivity type and a layer of second conductivity type.
 - (Original) The device of claim 26 further comprising:
 - a first contact electrically connected to the first layer of first conductivity type; and

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a second contact electrically connected to the textured layer.

- 28. (Original) The device of claim 27 wherein a surface of the second contact adjacent to the textured layer is substantially flat, the device further comprising at least one void disposed between the textured layer and the second contact.
 - 29. (Original) The device of claim 28 wherein the void is filled with air.
- 30. (Original) The device of claim 26 further comprising a polarization selection layer.
- 31. (Original) The device of claim 30 further comprising a substrate having a first surface and a second surface opposite the first surface, wherein the first layer of first conductivity type overlies the first surface and the polarization selection layer is disposed on the second surface.
- 32. (Original) The device of claim 30 wherein the polarization selection layer comprises a wire grid polarizer.
 - 33. (Original) The device of claim 26 further comprising: a submount;
 - a first interconnect connecting the first contact to the submount; and a second interconnect connecting the second contact to the submount.
 - 34. (Original) The device of claim 33 further comprising: a plurality of leads connected to the submount; and a lens overlying the submount.
 - 35. (Original) The device of claim 34 further comprising: a heat sink disposed between the leads and the submount.
- 36. (Original) The device of claim 26 wherein the textured layer comprises islands of semiconductor material and pockets.
- 37. (Original) The device of claim 36 wherein the islands of semiconductor material comprise about 10% to about 90% of a volume of the textured layer.
- 38. (Original) The device of claim 36 wherein the islands of semiconductor material comprise about 10% to about 50% of a volume of the textured layer.
 - 39. (Original) The device of claim 36 wherein the pockets are filled with air.
- 40. (Original) The device of claim 36 wherein the pockets are at least partially filled with a material having an index of refraction less than about 2.
- 41. (Original) The device of claim 36 wherein the second contact is formed over the textured layer and fills the pockets.

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- 42. (Original) The device of claim 26 wherein the textured layer has a thickness between about 200 Å and about 10,000 Å.
- 43. (Original) The device of claim 26 wherein the textured layer has a thickness between about 500 Å and about 4000Å.
 - (44.) (Original) A III-nittide light emitting device comprising:

a substrate having a first surface and a second surface opposite the first surface;

- a layer of first conductivity type formed on the first surface;
- a layer of second conductivity type;

an active region disposed between the layer of first conductivity type and the layer of second conductivity type; and

a textured layer formed on the second surface.

- 45. (Original) The device of claim 44 wherein the substrate is SiC.
- 46. (Original) The device of claim 44 wherein the textured layer comprises islands of semiconductor material and pockets.
- 47. (Original) The device of claim 46 wherein the islands of semiconductor material comprise about 10% to about 90% of a volume of the textured layer.
- 48. (Original) The device of claim 46 wherein the islands of semiconductor material comprise about 10% to about 50% of a volume of the textured layer.
- 49. (Original) The device of claim 44 wherein the textured layer has a thickness between about 200 Å and about 10,000 Å.
- 50. (Original) The device of claim 44 wherein the textured layer has a thickness between about 500 Å and about 4000Å.

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